9th RD50 Workshop

Report of Contributions

https://indico.cern.ch/e/6078

Contribution ID: **0** Type: **not specified**

Introduction

Presenters: BRUZZI, Mara; MOLL, Michael

Contribution ID: **1** Type: **not specified**

Visit to ATLAS experiment

Wednesday 18 October 2006 09:00 (2 hours)

Contribution ID: **2** Type: **not specified**

Introduction

Monday 16 October 2006 09:30 (15 minutes)

Presenters: BRUZZI, Mara; MOLL, Michael

Session Classification: Workshop Welcome

Contribution ID: **3** Type: **not specified**

Results of the simultaneous investigation of the microwave probed photoconductivity and current transients in proton irradiated FZ Si pad detectors

Monday 16 October 2006 09:45 (20 minutes)

E.Gaubas, J.Vaitkus, E.Fretwurst
Vilnius university, Hamburg university

Presenter: GAUBAS, Eugenijus (Vilnius)

Session Classification: Defect and Material Characterization & New Materials

Contribution ID: **4** Type: **not specified**

Recent results on CdZnTe and SiGe devices

Monday 16 October 2006 10:05 (20 minutes)

A. Ruzin, I. Torchinsky, P. Litovchenko
Tel Aviv University, Institute for Nuclear research - Kiev

Presenter: RUZIN, Arie (Tel Aviv University)

Session Classification: Defect and Material Characterization & New Materials

Contribution ID: **5** Type: **not specified**

Discussion Session (Defect and Material Characterization & New Materials)

Monday 16 October 2006 10:55 (30 minutes)

- Report from the Hamburg Workshop
- Plan for future work

Session Classification: Defect and Material Characterization & New Materials

Contribution ID: **6** Type: **not specified**

DC bias effects in CV measurements

Monday 16 October 2006 11:25 (20 minutes)

A.Chilingarov, D.Campbell
Lancaster University, UK

Presenter: CHILINGAROV, Alexander (Lancaster University, UK)

Session Classification: Pad Detector Characterization & Material Engineering

Contribution ID: **7** Type: **not specified**

Effect of bias voltage on full depletion voltage measured for different materials

Monday 16 October 2006 11:45 (20 minutes)

G.Kramberger, V. Cindro, I. Mandić, M. Mikuž
Jožef Stefan Institute, Ljubljana, Slovenia

Presenter: KRAMBERGER, Gregor (Jozef Stefan Institute)

Session Classification: Pad Detector Characterization & Material Engineering

Contribution ID: **8** Type: **not specified**

Discussion Session (Pad Detector Characterization & Material Engineering)

Monday 16 October 2006 17:00 (30 minutes)

Presenters: FRETWURST, Eckhart; KRAMBERGER, Gregor

Session Classification: Pad Detector Characterization & Material Engineering

Contribution ID: **9** Type: **not specified**

Neutron irradiation effects in epitaxial silicon detectors

Monday 16 October 2006 13:30 (20 minutes)

V. Khomenkov(*), D.Bisello(*), A. Candelori(*), V. Cindro
(*), A. Litovchenko(*), D. Pantano(*)
(*) INFN Padua Section and University of Padua, Italy
(**) Jožef Stefan Institute, Ljubjana, Slovenia

Presenter: KHOMENKOV, Vladimir (INFN)

Session Classification: Pad Detector Characterization & Material Engineering

Contribution ID: **10** Type: **not specified**

Homogeneity and thermal donors in p-type MCz-Si detector materials

Monday 16 October 2006 14:10 (20 minutes)

Panja Luukka et al.
Helsinki Institute of Physics

Presenter: LUUKKA, Panja (Helsinki)

Session Classification: Pad Detector Characterization & Material Engineering

Contribution ID: **11** Type: **not specified**

CCE and CV/IV measurements and annealing studies with irradiated p-type MCz diodes

Monday 16 October 2006 14:30 (20 minutes)

H. Hoedlmoser, M. Moll, M. Koehler, H. Nordlund
CERN, University Siegen, Helsinki Institute of Physics

Presenter: HOEDLMOSER, Herbert

Session Classification: Pad Detector Characterization & Material Engineering

Contribution ID: **12** Type: **not specified**

Charge collection in p- and n-type MCz Si microstrip and single pad SMART detectors irradiated with 26MeV protons

Monday 16 October 2006 14:50 (20 minutes)

Monica Scaringella, Carlo Tosi, Anna Macchiolo, David Menichelli, Mara Bruzzi, H. F. W. Sadrozinski, M. K. Petterson, C. Betancourt, A. Messineo, L. Borrello, N. Manna, D. Creanza
INFN Florence, University of Florence, SCIPP, INFN Pisa, University of Bari

Presenter: SCARINGELLA, Monica (INFN, University of Florence)

Session Classification: Pad Detector Characterization & Material Engineering

Contribution ID: **13** Type: **not specified**

Collaboration Board Meeting

Monday 16 October 2006 18:00 (1 hour)

Session Classification: Collaboration Board Meeting

Contribution ID: **14** Type: **not specified**

Update of 3D activity at ITC-irst

Tuesday 17 October 2006 09:00 (20 minutes)

Maurizio Boscardin
ITC-irst Trento (Italy)

Presenter: BOSCARDIN, Maurizio (ITC-irst)

Session Classification: 3D Detectors & New Structures

Contribution ID: **15** Type: **not specified**

Characterisation of a 3D-stc p-type prototype module read out with ATLAS SCT electronics

Tuesday 17 October 2006 09:20 (20 minutes)

S.Eckert 1, M.Boscardin 2, G.-F.Dalla Betta 2, T.Ehrich 1,
K.Jakobs 1, S.KÃ¼hn 1, M.Maassen 1, U.Parzefall 1,
C.Piemonte 2, A.Pozza 2, S.Ronchin 2, N.Zorzi 2
1 University of Freiburg, 2 ITC-irst, Trento

Presenter: ECKERT, Simon (University of Freiburg)

Session Classification: 3D Detectors & New Structures

Contribution ID: **16** Type: **not specified**

Discussion Session (3D detectors and New Structures)

Tuesday 17 October 2006 09:40 (30 minutes)

Session Classification: 3D Detectors & New Structures

Contribution ID: **17** Type: **not specified**

Measurements of Lorentz angle in irradiated silicon strip sensors

Monday 16 October 2006 16:40 (20 minutes)

J. Bol, W. de Boer, A. Furgeri, F. Hauler, M. Krause, S. Mueller, S. Reinhardt, A. Sabellek
Institut für Experimentelle Kernphysik, University of Karlsruhe

Presenter: KRAUSE, Michael (University of Karlsruhe)

Session Classification: Pad Detector Characterization & Material Engineering

Contribution ID: **18** Type: **not specified**

Absolute charge measurements using laser setup.

Tuesday 17 October 2006 10:40 (20 minutes)

Peter Kodys and Prague group
Charles University

Presenter: KODYS, Peter (Prague)

Session Classification: Full Detector Systems

Contribution ID: **19** Type: **not specified**

Negative charge measurements with ATLAS SCT readout HW and SW.

Tuesday 17 October 2006 11:00 (20 minutes)

Peter Kodys and Prague group
Charles University

Presenter: KODYS, Peter (Charles University, Prague)

Session Classification: Full Detector Systems

Contribution ID: **20** Type: **not specified**

Annealing of TID radiation effects in SMART SSD, MOS and Capacitance test structures

Tuesday 17 October 2006 11:20 (20 minutes)

H. F.-W. Sadrozinski, C. Betancourt, R. Heffern, I. Henderson, J. Pixley, A. Polyakov, M. Wilder M. Boscardin, C. Piemonte, A. Pozza,N. Zorzi, G.-F. Dalla Betta
UC Santa Cruz, ITC-irst, Univ. of Trento

Presenter: SADROZINSKI, Hartmut (SCIPP)

Session Classification: Full Detector Systems

Contribution ID: **21** Type: **not specified**

Gamma and Neutron Radiation Hardness Tests on 3 different SiGe IHP Technologies for S-LHC

Tuesday 17 October 2006 11:40 (20 minutes)

S. Díez, M. Ullán, F. Campabadal, M. Lozano, G. Pellegrini
CNM - Barcelona

Presenter: DÍEZ, Sergio (CNM - Barcelona)

Session Classification: Full Detector Systems

Contribution ID: **22** Type: **not specified**

Discussion Session (Full Detector Systems)

Tuesday 17 October 2006 12:20 (30 minutes)

Presenter: CASSE, Gian (Liverpool University)

Session Classification: Full Detector Systems

Contribution ID: **23** Type: **not specified**

Recent results of measurements performed on irradiated epitaxial and MCz silicon devices of the SMART Collaboration

Monday 16 October 2006 13:50 (20 minutes)

M. Boscardin, L. Borrello, M. Bruzzi, D. Creanza, G.F. Dalla Betta, V. Eremin, A. Macchiolo, N. Manna, D. Menichelli, A. Messineo, C. Piemonte, V. Radicci, M. Scaringella, C. Tosi, E. Verbitskaya, N. Zorzi

Presenter: MACCHIOLO, Anna

Session Classification: Pad Detector Characterization & Material Engineering

Contribution ID: **24** Type: **not specified**

Charge collection of p-type detectors irradiated with neutrons

Tuesday 17 October 2006 12:00 (20 minutes)

C. Lacasta S. Martí, G. Pellegrini, F.Campabadal,
C.Escobar, C. García, M. Miñano, M. Lozano, J.M. Rafi,
M.Ullan
IFIC-Valencia CNM-IMB

Presenter: LACASTA, Carlos (IFIC)

Session Classification: Full Detector Systems

Contribution ID: **25** Type: **not specified**

Modeling Radiation Damage Effects in Oxygenated Silicon Detectors

Monday 16 October 2006 15:40 (20 minutes)

M. Petasecca (1,2), G. Caprai (1), G.U. Pignatel (1,2), D. Passeri (1,2)
(1) University of Perugia, via G.Duranti 93 - 06125 Perugia ITALY (2) INFN sez. Perugia, via Pascoli 10 – 06120 Perugia ITALY

Presenter: PETASECCA, Marco (University of Perugia - DIEI)

Session Classification: Pad Detector Characterization & Material Engineering

Contribution ID: **26** Type: **not specified**

Electric field distribution in irradiated MCZ Si detectors

Monday 16 October 2006 16:00 (20 minutes)

E. Verbitskaya et al.

Presenter: VERBITSKAYA, Elena (Ioffe)

Session Classification: Pad Detector Characterization & Material Engineering

Contribution ID: **27** Type: **not specified**

Recent results on electric field distribution in SMART irradiated detectors on MCZ and epitaxial silicon

Monday 16 October 2006 16:20 (20 minutes)

V. Eremin et al.

Presenter: EREMIN, Vladimir (Ioffe)

Session Classification: Pad Detector Characterization & Material Engineering